

HACKX 2025

Dquad

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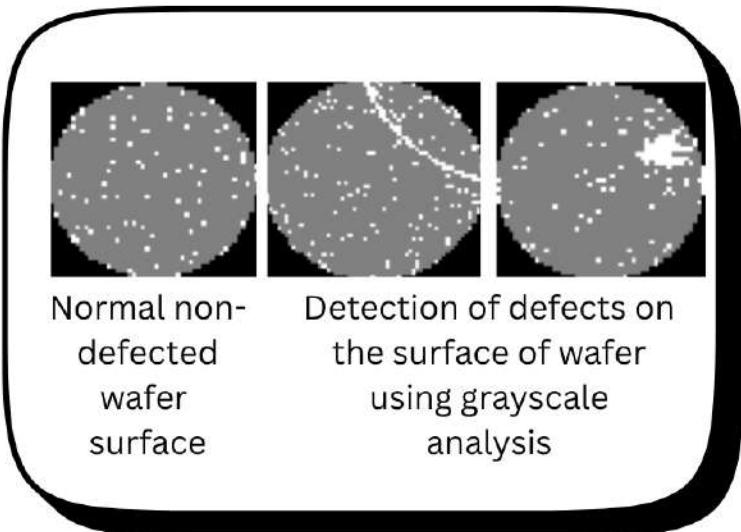
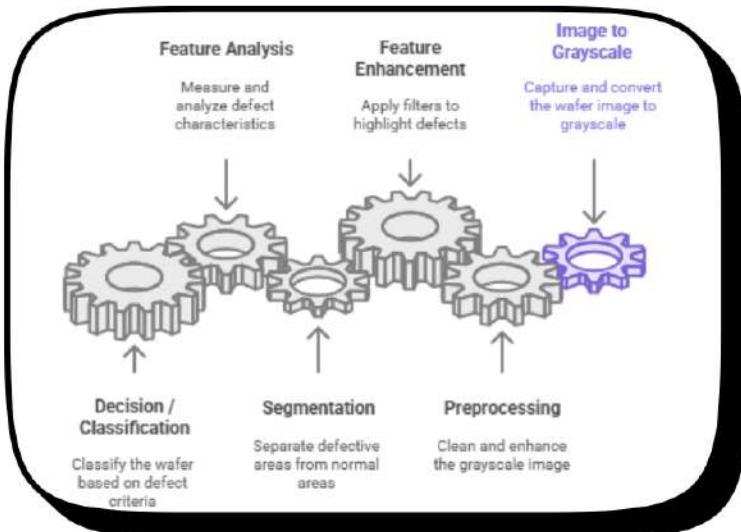


Presence of Undetected defects

(micro-cracks, dents) on the surface of semiconductor wafers



Defects (Micro-Crack and Dents)
Detection of Semiconductor Wafers
using Grayscale Image Processing



- ✓ Grayscale Image-Based Defect Detection
- ✓ Automated Microcrack & Dent Identification
- ✓ Image Preprocessing & Edge Detection
- ✓ Feature Extraction

- Enhanced Quality control
- Increased Yield
- Reduced human dependencies
- Sustainability
- Scalability